

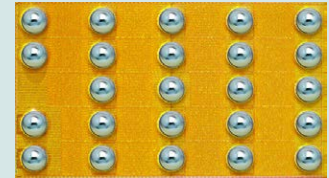
## EPC2030 – Enhancement Mode Power Transistor

 $V_{DS}$ , 40 V $R_{DS(on)}$ , 2.4 m $\Omega$  $I_D$ , 48 A

Gallium Nitride's exceptionally high electron mobility and low temperature coefficient allows very low  $R_{DS(on)}$ , while its lateral device structure and majority carrier diode provide exceptionally low  $Q_G$  and zero  $Q_{RR}$ . The end result is a device that can handle tasks where very high switching frequency, and low on-time are beneficial as well as those where on-state losses dominate.

## Maximum Ratings

PARAMETER		VALUE	UNIT
$V_{DS}$	Drain-to-Source Voltage (Continuous)	40	V
	Drain-to-Source Voltage (up to 10,000 5 ms pulses at 150°C)	48	
$I_D$	Continuous ( $T_A = 25^\circ\text{C}$ , $R_{\theta JA} = 6^\circ\text{C/W}$ )	48	A
	Pulsed ( $25^\circ\text{C}$ , $T_{PULSE} = 300 \mu\text{s}$ )	490	
$V_{GS}$	Gate-to-Source Voltage	6	V
	Gate-to-Source Voltage	-4	
$T_J$	Operating Temperature	-40 to 150	$^\circ\text{C}$
$T_{STG}$	Storage Temperature	-40 to 150	



EPC2030 eGaN® FETs are supplied only in passivated die form with solder bumps. Die Size: 4.6 mm x 2.6 mm

- High Speed DC-DC Conversion
- Motor Drive
- Industrial Automation
- Synchronous Rectification
- Class-D Audio

## Thermal Characteristics

PARAMETER		TYP	UNIT
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	0.45	$^\circ\text{C/W}$
$R_{\theta JB}$	Thermal Resistance, Junction-to-Board	3.9	
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient (Note 1)	45	

Note 1:  $R_{\theta JA}$  is determined with the device mounted on one square inch of copper pad, single layer 2 oz copper on FR4 board. See [https://epc-co.com/epc/documents/product-training/Appnote\\_Thermal\\_Performance\\_of\\_eGaN\\_FETs.pdf](https://epc-co.com/epc/documents/product-training/Appnote_Thermal_Performance_of_eGaN_FETs.pdf) for details.

Static Characteristics ( $T_J = 25^\circ\text{C}$  unless otherwise stated)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
$BV_{DSS}$	Drain-to-Source Voltage	$V_{GS} = 0 \text{ V}$ , $I_D = 1.1 \text{ mA}$	40			V
$I_{DSS}$	Drain-Source Leakage	$V_{GS} = 0 \text{ V}$ , $V_{DS} = 32 \text{ V}$		0.1	0.9	mA
$I_{GSS}$	Gate-to-Source Forward Leakage	$V_{GS} = 5 \text{ V}$		1	9	mA
	Gate-to-Source Reverse Leakage	$V_{GS} = -4 \text{ V}$		0.1	0.9	mA
$V_{GS(TH)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}$ , $I_D = 16 \text{ mA}$	0.8	1.5	2.5	V
$R_{DS(on)}$	Drain-Source On Resistance	$V_{GS} = 5 \text{ V}$ , $I_D = 30 \text{ A}$		1.8	2.4	m $\Omega$
$V_{SD}$	Source-Drain Forward Voltage	$I_S = 0.5 \text{ A}$ , $V_{GS} = 0 \text{ V}$		1.9		V

All measurements were done with substrate connected to source.

Dynamic Characteristics ( $T_j = 25^\circ\text{C}$  unless otherwise stated)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
$C_{ISS}$	Input Capacitance	$V_{DS} = 20\text{ V}, V_{GS} = 0\text{ V}$		1960	2360	pF
$C_{RSS}$	Reverse Transfer Capacitance			62		
$C_{OSS}$	Output Capacitance			1120	1680	
$C_{OSS(ER)}$	Effective Output Capacitance, Energy Related (Note 2)	$V_{DS} = 0\text{ to }20\text{ V}, V_{GS} = 0\text{ V}$		1440		
$C_{OSS(TR)}$	Effective Output Capacitance, Time Related (Note 3)			1600		
$R_G$	Gate Resistance			0.4		$\Omega$
$Q_G$	Total Gate Charge	$V_{DS} = 20\text{ V}, V_{GS} = 5\text{ V}, I_D = 30\text{ A}$		17	22	nC
$Q_{GS}$	Gate-to-Source Charge	$V_{DS} = 20\text{ V}, I_D = 30\text{ A}$		5.8		
$Q_{GD}$	Gate-to-Drain Charge			3.4		
$Q_{G(TH)}$	Gate Charge at Threshold			4.2		
$Q_{OSS}$	Output Charge	$V_{DS} = 20\text{ V}, V_{GS} = 0\text{ V}$		32	48	
$Q_{RR}$	Source-Drain Recovery Charge			0		

All measurements were done with substrate connected to source.

Note 2:  $C_{OSS(ER)}$  is a fixed capacitance that gives the same stored energy as  $C_{OSS}$  while  $V_{DS}$  is rising from 0 to 50%  $BV_{DSS}$ .

Note 3:  $C_{OSS(TR)}$  is a fixed capacitance that gives the same charging time as  $C_{OSS}$  while  $V_{DS}$  is rising from 0 to 50%  $BV_{DSS}$ .

Figure 1: Typical Output Characteristics at  $25^\circ\text{C}$

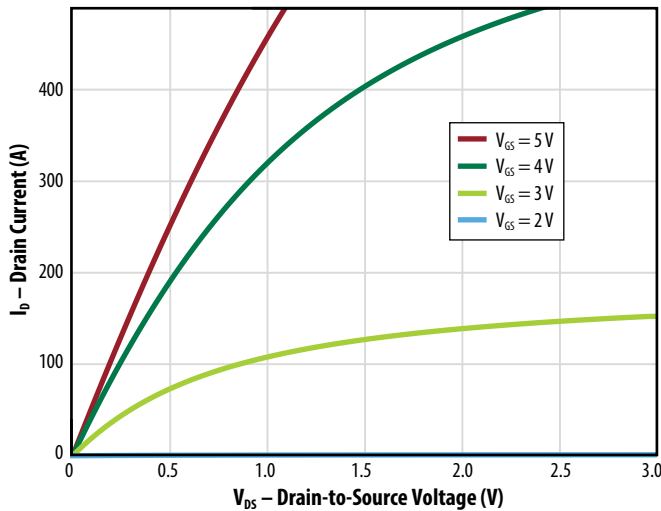


Figure 2: Transfer Characteristics

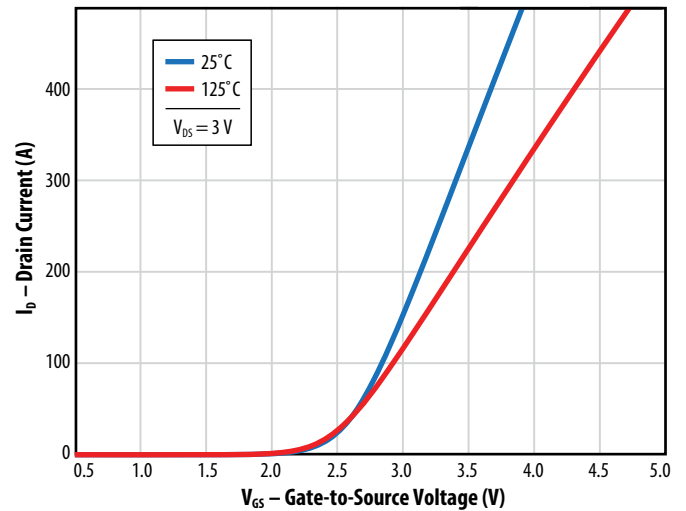


Figure 3:  $R_{DS(on)}$  vs.  $V_{GS}$  for Various Drain Currents

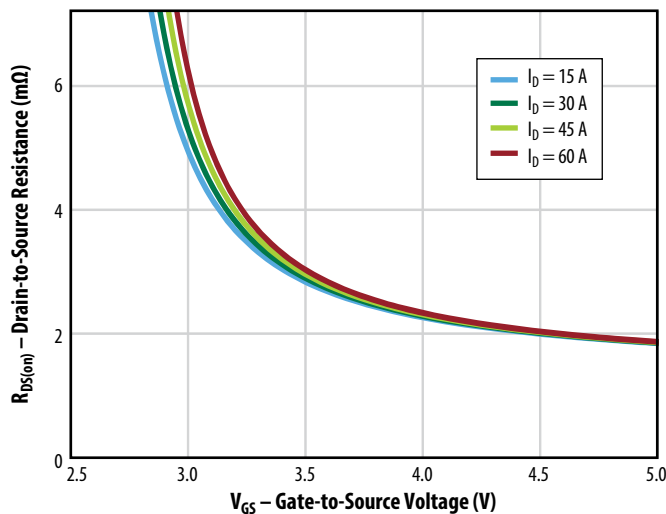


Figure 4:  $R_{DS(on)}$  vs.  $V_{GS}$  for Various Temperatures

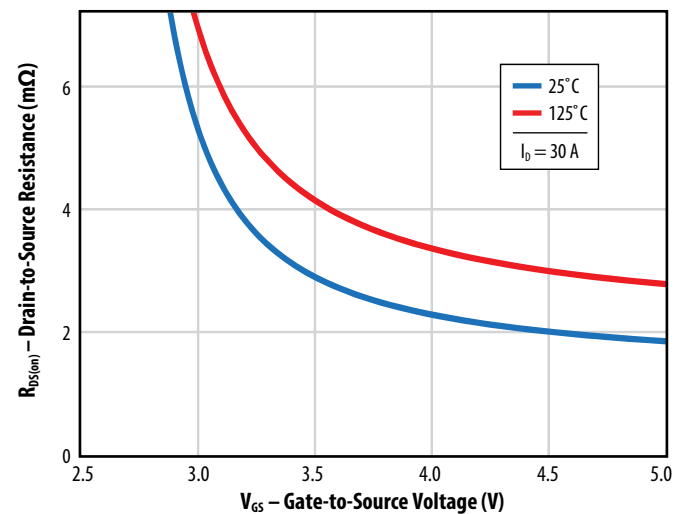


Figure 5a: Capacitance (Linear Scale)

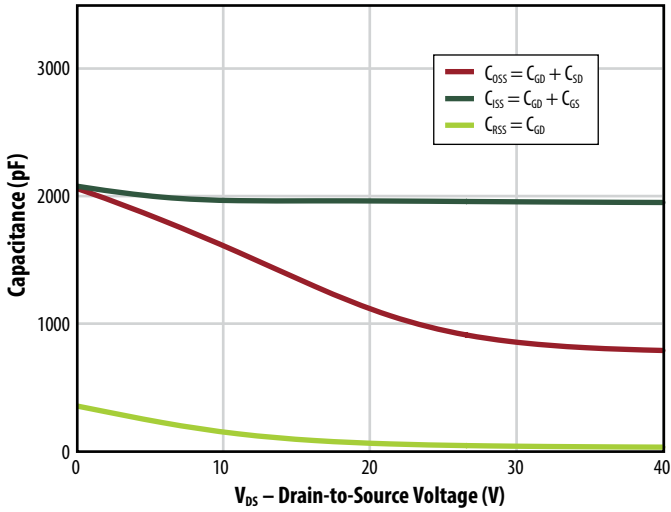


Figure 5b: Capacitance (Log Scale)

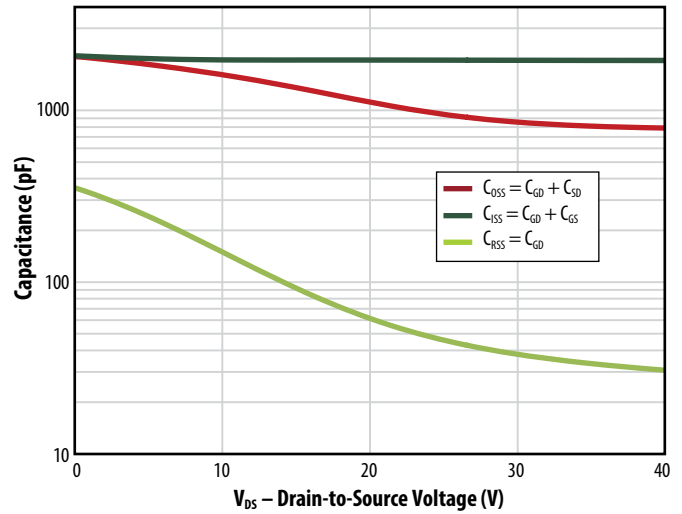


Figure 6: Output Charge and  $C_{OSS}$  Stored Energy

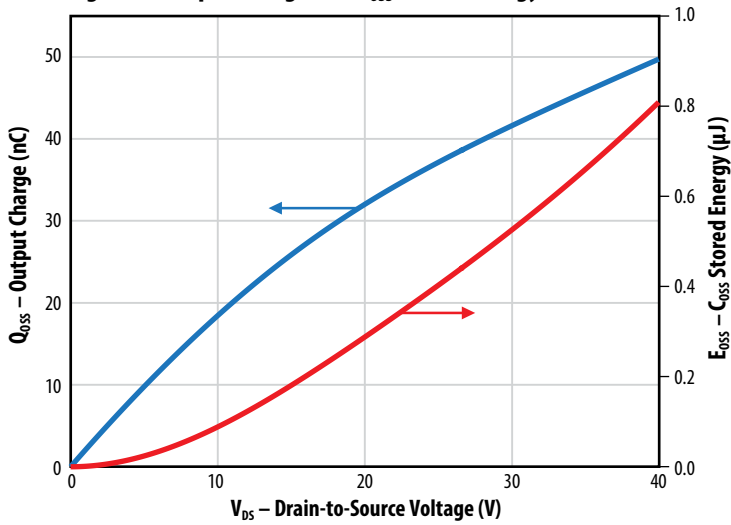


Figure 7: Gate Charge

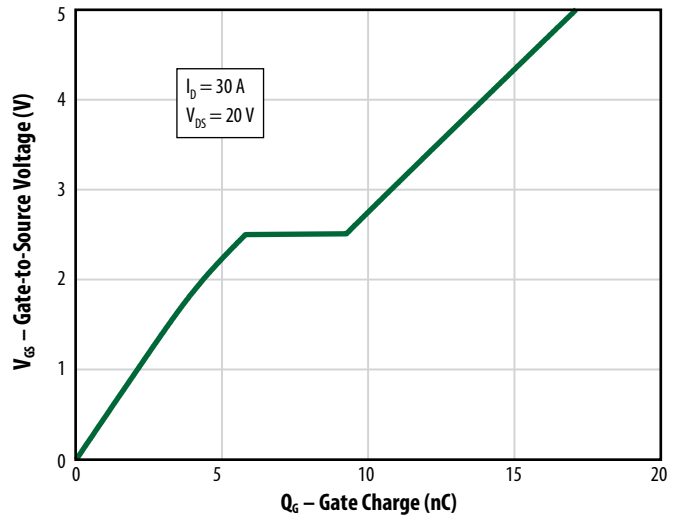


Figure 8: Reverse Drain-Source Characteristics

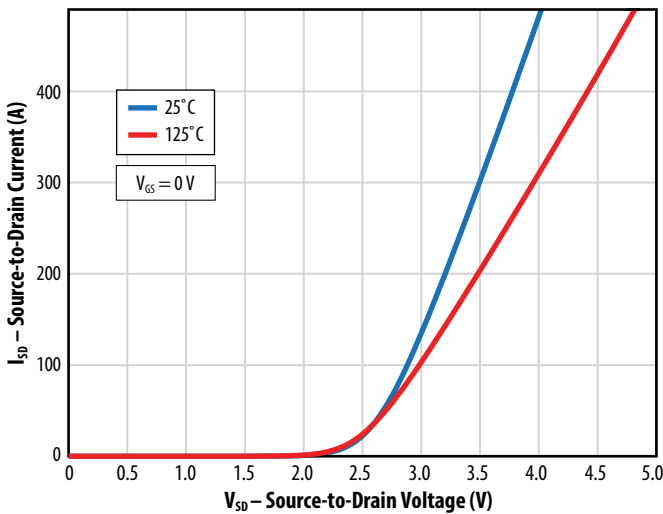
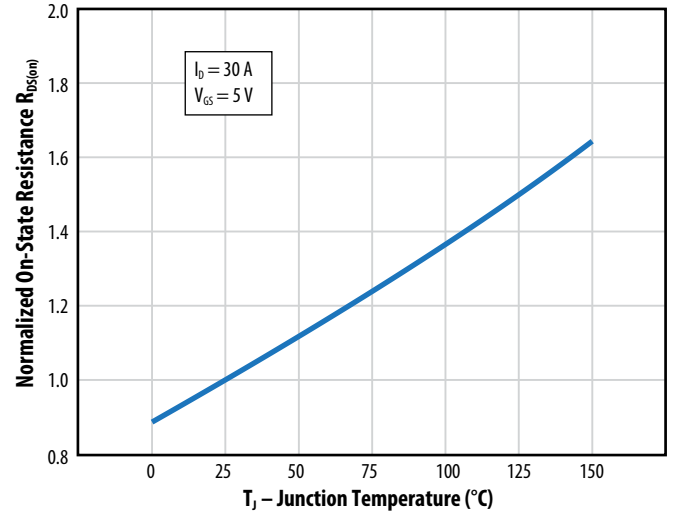


Figure 9: Normalized On-State Resistance vs. Temperature



All measurements were done with substrate shorted to source.

Figure 10: Normalized Threshold Voltage vs. Temperature

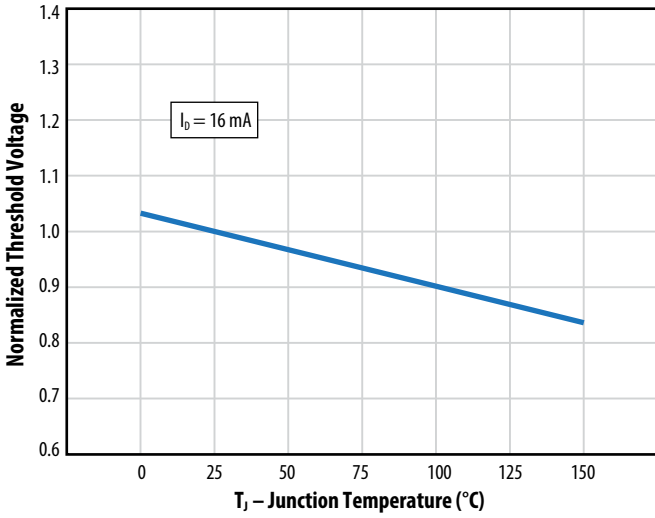


Figure 11: Safe Operating Area

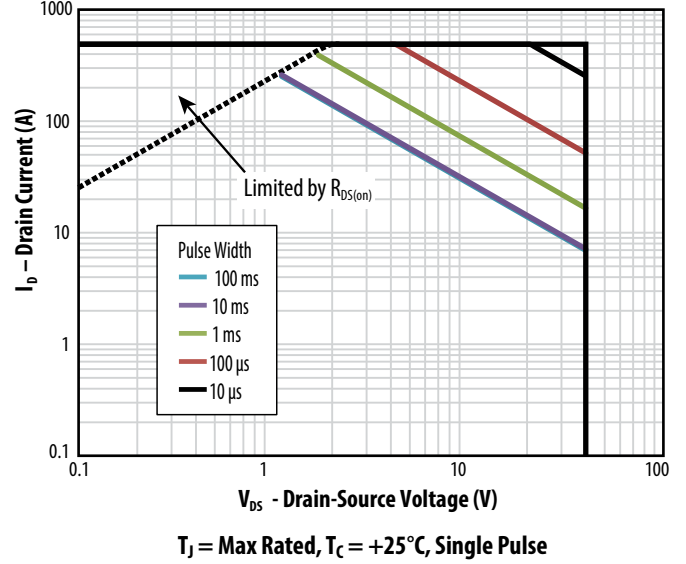
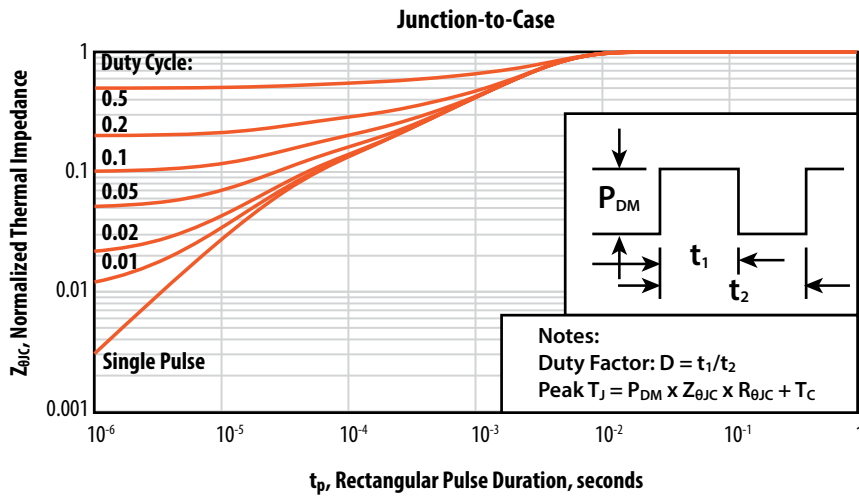
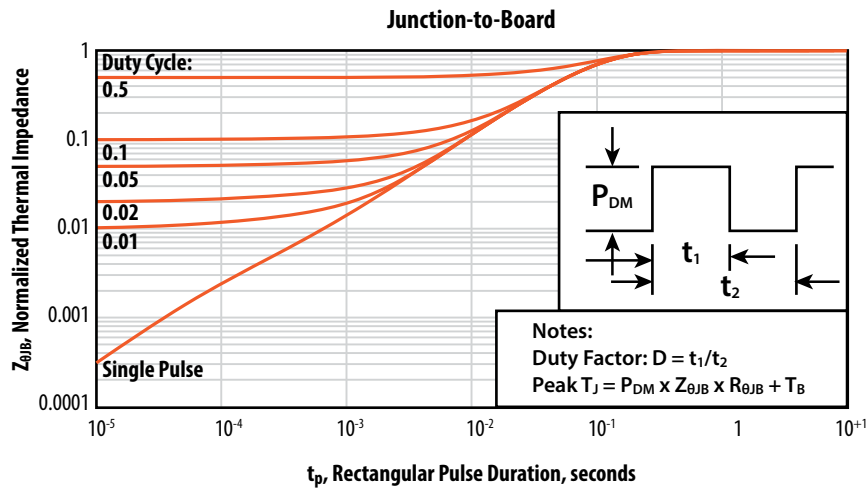
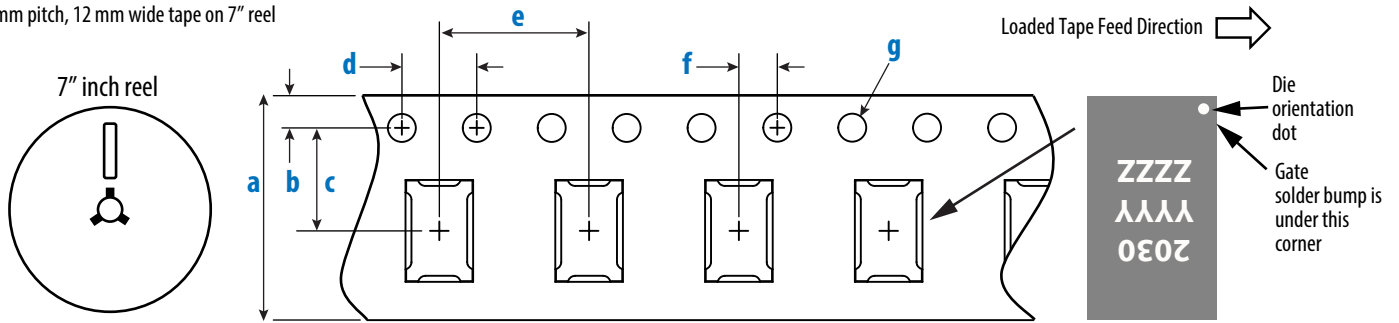


Figure 12: Transient Thermal Response Curves



**TAPE AND REEL CONFIGURATION**

8 mm pitch, 12 mm wide tape on 7" reel

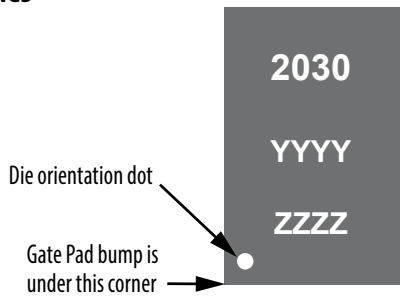


EPC2030 (Note 1)	Dimension (mm)		
	Target	MIN	MAX
<b>a</b>	12.00	11.90	12.30
<b>b</b>	1.75	1.65	1.85
<b>c</b> (Note 2)	5.50	5.45	5.55
<b>d</b>	4.00	3.90	4.10
<b>e</b>	8.00	7.90	8.10
<b>f</b> (Note 2)	2.00	1.95	2.05
<b>g</b>	1.50	1.50	1.60

Note 1: MSL 1 (moisture sensitivity level 1) classified according to IPC/ JEDEC industry standard.  
 Note 2: Pocket position is relative to the sprocket hole measured as true position of the pocket, not the pocket hole.

Die is placed into pocket solder bump side down (face side down)

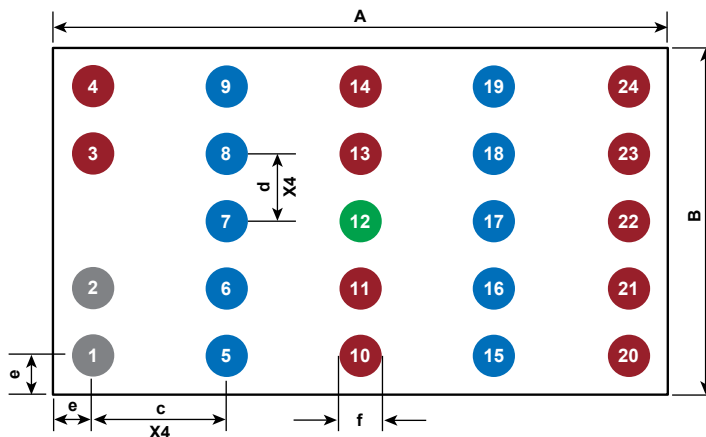
**DIE MARKINGS**



Part Number	Laser Markings		
	Part # Marking Line 1	Lot _Date Code Marking Line 2	Lot _Date Code Marking Line 3
EPC2030	2030	YYYY	ZZZZ

**DIE OUTLINE**

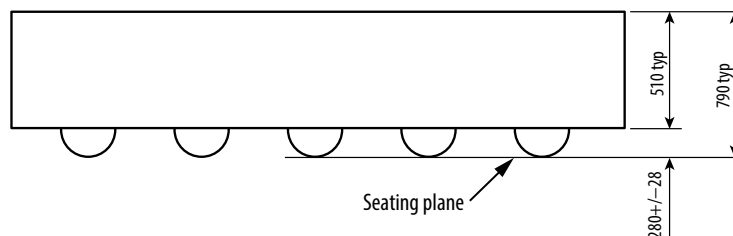
Solder Bump View



DIM	Micrometers		
	MIN	Nominal	MAX
<b>A</b>	4570	4600	4630
<b>B</b>	2570	2600	2630
<b>c</b>	1000	1000	1000
<b>d</b>	500	500	500
<b>e</b>	285	300	315
<b>f</b>	332	369	406

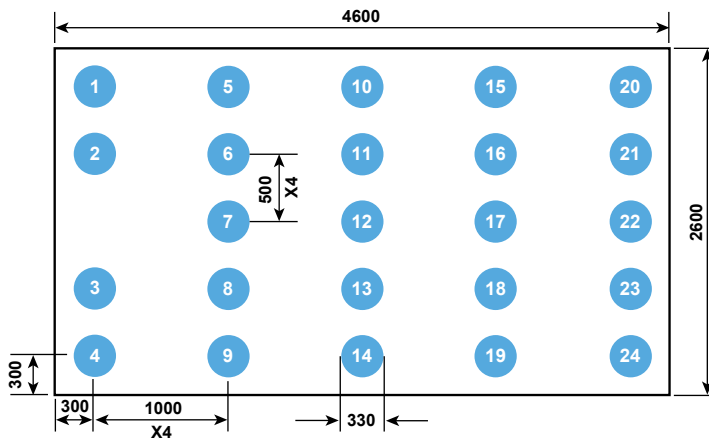
Pads 1 and 2 are Gate;  
 Pads 5, 6, 7, 8, 9, 15, 16, 17, 18, 19 are Drain;  
 Pads 3, 4, 10, 11, 13, 14, 20, 21, 22, 23, 24 are Source;  
 Pad 12 is Substrate\*

Side View



\*Substrate pin should be connected to Source

**RECOMMENDED LAND PATTERN**  
(units in  $\mu\text{m}$ )

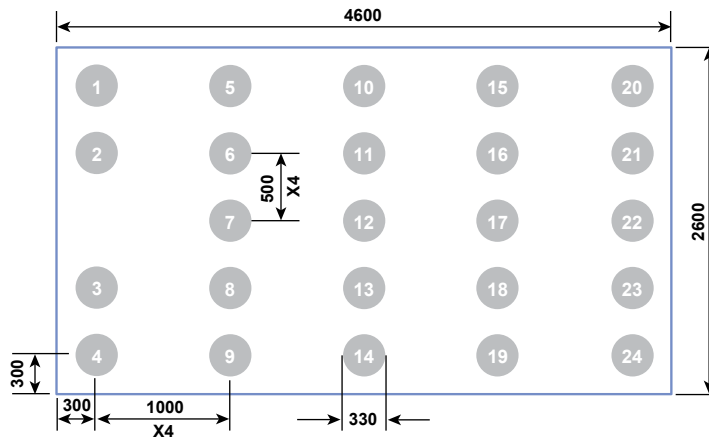


Land pattern is solder mask defined  
Solder mask opening is 330  $\mu\text{m}$   
It is recommended to have on-Cu trace PCB vias  
  
Pads 1 and 2 are Gate;  
Pads 5, 6, 7, 8, 9, 15, 16, 17, 18, 19 are Drain;  
Pads 3, 4, 10, 11, 13, 14, 20, 21, 22, 23, 24 are Source;  
Pad 12 is Substrate\*

\*Substrate pin should be connected to Source

**RECOMMENDED STENCIL DRAWING**  
(units in  $\mu\text{m}$ )

Option 1 : Intended for use with SAC305 Type 4 solder.

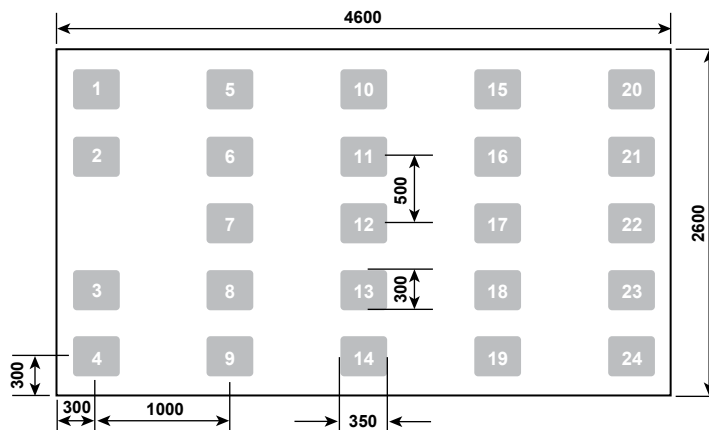


Recommended stencil should be 4 mil (100  $\mu\text{m}$ ) thick, must be laser cut, openings per drawing.

Additional assembly resources available at  
<https://epc-co.com/epc/DesignSupport/AssemblyBasics.aspx>

**RECOMMENDED STENCIL DRAWING**  
(units in  $\mu\text{m}$ )

Option 2 : Intended for use with SAC305 Type 3 solder.



Recommended stencil should be 4 mil (100  $\mu\text{m}$ ) thick, must be laser cut, openings per drawing.

Additional assembly resources available at  
<https://epc-co.com/epc/DesignSupport/AssemblyBasics.aspx>

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